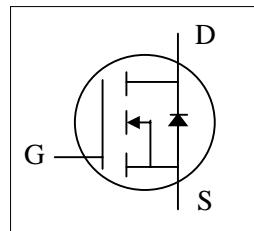




- ▼ Simple Drive Requirement
- ▼ Low On-resistance
- ▼ Fast Switching Characteristic
- ▼ RoHS Compliant & Halogen-Free

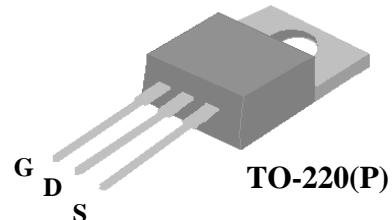


$BV_{DSS}$	40V
$R_{DS(ON)}$	4.2mΩ
$I_D$	150A

## Description

Advanced Power MOSFETs from APEC provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is widely preferred for commercial-industrial power applications and suited for low voltage applications such as DC/DC converters.



## Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	40	V
$V_{GS}$	Gate-Source Voltage	+20	V
$I_D @ T_c = 25^\circ C$	Continuous Drain Current (Chip)	150	A
$I_D @ T_c = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^3$	80	A
$I_D @ T_c = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^3$	80	A
$I_{DM}$	Pulsed Drain Current <sup>1</sup>	320	A
$P_D @ T_c = 25^\circ C$	Total Power Dissipation	156	W
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C

## Thermal Data

Symbol	Parameter	Value	Units
$R_{thj-c}$	Maximum Thermal Resistance, Junction-case	0.8	°C/W
$R_{thj-a}$	Maximum Thermal Resistance, Junction-ambient	62	°C/W



### Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	40	-	-	V
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=60\text{A}$	-	-	4.2	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	2	-	4	V
$g_{\text{fs}}$	Forward Transconductance	$V_{\text{DS}}=10\text{V}, I_{\text{D}}=60\text{A}$	-	90	-	S
$I_{\text{DSS}}$	Drain-Source Leakage Current	$V_{\text{DS}}=40\text{V}, V_{\text{GS}}=0\text{V}$	-	-	25	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Source Leakage	$V_{\text{GS}}= \pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	$\pm 100$	$\text{nA}$
$Q_g$	Total Gate Charge <sup>2</sup>	$I_{\text{D}}=40\text{A}$	-	58	93	$\text{nC}$
$Q_{\text{gs}}$	Gate-Source Charge	$V_{\text{DS}}=32\text{V}$	-	12	-	$\text{nC}$
$Q_{\text{gd}}$	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=10\text{V}$	-	26	-	$\text{nC}$
$t_{\text{d}(\text{on})}$	Turn-on Delay Time <sup>2</sup>	$V_{\text{DS}}=20\text{V}$	-	14	-	ns
$t_r$	Rise Time	$I_{\text{D}}=40\text{A}$	-	83	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_G=1\Omega$	-	25	-	ns
$t_f$	Fall Time	$V_{\text{GS}}=10\text{V}$	-	10	-	ns
$C_{\text{iss}}$	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	2600	4160	$\text{pF}$
$C_{\text{oss}}$	Output Capacitance	$V_{\text{DS}}=25\text{V}$	-	600	-	$\text{pF}$
$C_{\text{rss}}$	Reverse Transfer Capacitance	f=1.0MHz	-	260	-	$\text{pF}$
$R_g$	Gate Resistance	f=1.0MHz	-	1.4	2.8	$\Omega$

### Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$V_{\text{SD}}$	Forward On Voltage <sup>2</sup>	$I_{\text{S}}=40\text{A}, V_{\text{GS}}=0\text{V}$	-	-	1.2	V
$t_{\text{rr}}$	Reverse Recovery Time <sup>2</sup>	$I_{\text{S}}=10\text{A}, V_{\text{GS}}=0\text{V},$	-	43	-	ns
$Q_{\text{rr}}$	Reverse Recovery Charge	$dI/dt=100\text{A}/\mu\text{s}$	-	54	-	$\text{nC}$

### Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Package limitation current is 80A.

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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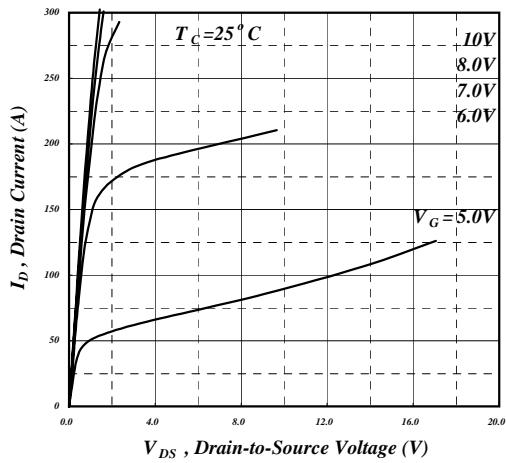


Fig 1. Typical Output Characteristics

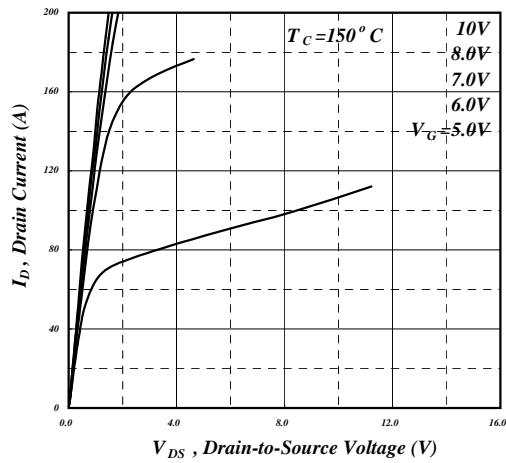


Fig 2. Typical Output Characteristics

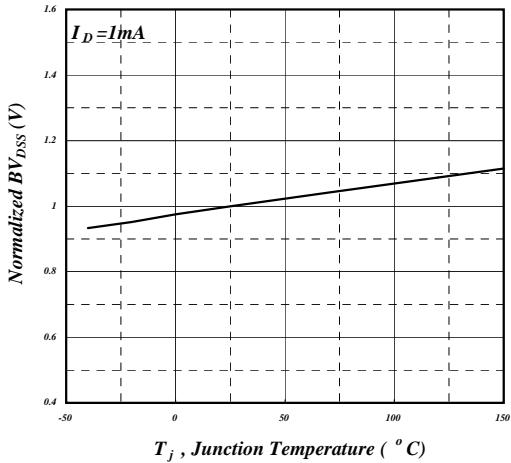
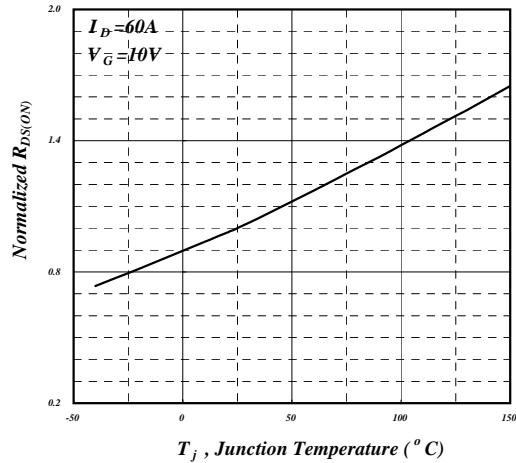
Fig 3. Normalized  $BV_{DSS}$  v.s. Junction Temperature

Fig 4. Normalized On-Resistance v.s. Junction Temperature

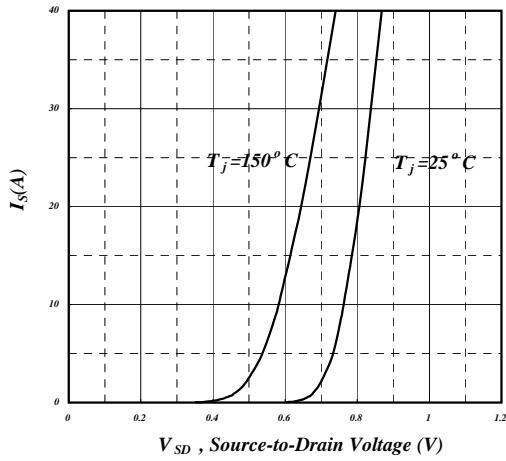


Fig 5. Forward Characteristic of Reverse Diode

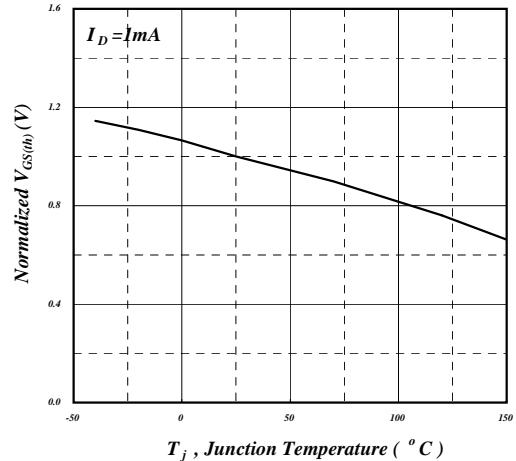


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

